

Search Notes

Application/Control No.

10/657,100

Examiner

Khai M. Nguyen

Applicant(s)/Patent under
Reexamination

ARAKAWA, TAKEHARU

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
see	previous		KN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see previous)		KN